

Double diffractive crosssection measurement at TOTEM experiment

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Motivation

Why to measure double diffractive cross-section?

- Contributes to understanding of proton structure
- Size and opacity of proton
- Tests non-perturbative QCD models
- Important part of the pp inelastic cross-section
- No precise measurements at high η ($|\eta|$ >4.2) and \sqrt{s} >2 TeV
- Important step on understanding background for central diffractive Higgs measurements

Classification of inelastic events



 $\sigma_{TOT} = \sigma_{EL} + \sigma_{ND} + \sigma_{SD} + \sigma_{DD} + \sigma_{CD}$

Note: Non-diffractive events will be called minimum bias (MB) later in the presentation

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TOTEM has two charged particle trackers



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Pure event sample of DD events



Event selection (2T2+0T1)

- At least one T2 track on both positive and negative sides
 - No cut on Z_{impact} to select events with neutral particles hitting beam pipe
- No tracks on T1s

Trigger requirement ◆ At least one track in T2

Pure event sample of DD events: MC predictions

| Pythia 8 | 3 | | | | |
|------------|-----------------------|--|--|---------------------|-----|
| | Cross-section (mb) | Acceptance (%) | Example integrated luminosity (µb ⁻¹) | Number of events | |
| DD | 8.1 | 2.4% | 40 | 7614 | |
| SD | 12.4 | 0.06% | 40 | 288 | |
| MB | 50.9 | 0.04% | 40 | 774 | S/(|
| Phojet | | | | | |
| | Cross-section (mb) | Acceptance (%) | Example integrated luminosity (µb ⁻¹) | Number of events | Sa |
| DD | 3.9 | 2.9% | 40 | 4524 | |
| SD | 10.7 | 0.02% | 40 | 64 | |
| СЕР | 1.3 | 0.01% | 40 | 5 | |
| MB | 61.6 | 0.02% | 40 | 370 | |
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Cross section from counting experiment

$$\sigma_{DD} = \frac{cN_{data}^{raw} - N_{background}}{AL}$$

- N_{data}^{raw} = Raw number of data events passing event selection
- $N_{background}$ = Estimate of number of background events passing event selection
- c = Experimental efficiency (trigger efficiency, reconstruction inefficiency, pile-up correction)
- A = Acceptance of double diffractive events with the selection
- L = Integrated luminosity

MB background estimation method

Select control sample that is dominated by MB: tracks in both T2s and both T1s
Calculate amount of MB in control sample (csample)

$$N_{MB}^{csample} = N_{data}^{csample} - N_{DD}^{csample} - N_{SD}^{csample} - N_{CEP}^{csample}$$

Calculate ratio R from MC

$$R_{MB} = \frac{N_{signalsample}^{MBMC}}{N_{csample}^{MBMC}}$$

Correct for difference in ratios between MC and data

$$C = \frac{R_{total}^{data}}{R_{total}^{MC}}$$

MB background

$$N_{MB}^{background} = R_{MB} C \cdot N_{MB}^{csample}$$

Iterate for amount of DD in control sample

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MB background estimate



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Data-based SD background estimate

Event selection of clean SD events from data to test relative fractions of different categories

Exactly one proton in Roman Pots
T2 & T1 selection the same as in this analysis
Events triggered with T2 trigger

SD background estimation method

Select control sample as 1T2+0T1
Take ratio between control sample and wanted sample from data
Calculate SD

background based on the two numbers



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Background estimates will be verified with other selections



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Summary

•Double diffractive cross-section measurement tests non-perturbative QCD models and it is an important step on understanding background for central diffractive Higgs measurements

•Event selection that requires tracks in TOTEM T2s and vetos for T1 tracks has high purity (>90%) for double diffractive events

Single diffractive background can be estimated with data-based method
 Non-diffractive background estimation method a combination of data and MC

•STAY TUNED FOR THE CROSS-SECTION MEASUREMENT FROM DATA!